Notice of References Cited	Application/Control No. 10/581,959	Applicant(s)/Patent Under Reexamination YOON, IL SHIK		
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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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	Ν	JP 03293276 A	12-1991	Japan	ENDO, MASAHIKO	B66B 5/00
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NON-PATENT DOCUMENTS

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